

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/750,146	SHIH, WEI-YAN
	Examiner	Art Unit
	Richard Hanig	2873

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
354	291 290	03/03/05	MH
	223 224		
	225 226		